

Automotive Electronics Council

Component Technical Committee

Agenda

(subject to change)

**2014 - Sixteenth Annual
Automotive Electronics
Reliability Workshop**

April 22, 23, & 24

**Novi, MI
Sheraton Detroit Novi Hotel**

Tuesday, April 22, 2014

7:30 am - 8:00 am					Continental Breakfast (provided)
8:00 am - 8:30 am					Workshop Introductions
Session 1: Passive/Discrete Component Technology 8:30 am - 10:30 am	1.1	8:30 am - 9:00 am	Jayson Young <i>KEMET</i>	Polymer Tantalum Capacitors for Automotive Applications	
	1.2	9:00 am - 9:30 am	Reiner Kuehl <i>Vishay BC Components</i>	Stability of Components During Biased Humidity Testing and Application	
	1.3	9:30 am - 10:00 am	Peter Blais <i>KEMET</i>	SMD and Leaded Ceramic Capacitors For High Temperature Applications	
	1.4	10:00 am - 10:30 am	Charles Pothier <i>Vishay Intertechnology</i>	New Tantalum Capacitor Technologies Ensure Reliability in the Next Generation of Automotive Electronics	
10:30 am - 11:00 am					BREAK: Coffee, drinks, snacks (provided)
Workshop Session - W.1		11:00 am - 12:00 pm	LED Qualification Review & Discussion <i>Moderator: Ludger Kappius, Hella KGaA</i>		
12:00 pm - 1:30 pm					LUNCH (on own)
Workshop Session - W.2		1:30 pm - 3:00 pm	Q200 Document Revision Status & Discussion <i>Moderator: AEC Q200 Technical Committee</i>		
3:00 pm - 3:30 pm					BREAK: coffee, drinks, snacks (provided)
Workshop Session - W.3		3:30 pm - 5:00 pm	Q101 Document Status & Discussion <i>Moderator: AEC Q101 Technical Committee</i>		
5:00 PM					SESSION CLOSE

Wednesday, April 23, 2014

7:30 am - 8:00 am Continental Breakfast (provided)				
Session 2: Semiconductor Technology - Part 1 8:00 am - 11:00 am	2.1	8:00 am - 8:30 am	Wolfgang Reinprecht <i>AMS</i>	Advanced Latch-up Testing of HV Automotive IC's
	2.2	8:30am - 9:00am	Warren Chen <i>Macronix International</i>	NAND Flash Qualification Challenges for Automotive Applications
	2.3	9:00 am - 9:30 am	Sebastiano Russo <i>STMicroelectronics</i>	Reliability of New Pb-Free Die Attach Materials for Power Devices
9:30 am - 10:00 am BREAK: Coffee, drinks, snacks (provided)				
Session 2: (Continued)	2.4	10:00 am - 10:30 am	Shin Low <i>Xilinx</i>	High Performance Flip Chip Packaging for High Reliability Semiconductor Devices
	2.5	10:30 am - 11:00 am	Eric Lei <i>Global Foundries</i>	Evaluation of 40LP SRAM HTOL 150degC for Automotive Grade 0 Application
Workshop Session - W.4	11:00 am - 12:00 pm	Robustness Validation and Failure Rates - "Sample Sizes in Reliability Testing" <i>Moderator: Werner Kanert, Infineon Technologies</i>		
12:00 pm - 1:30 pm LUNCH (on own)				

Wednesday, April 23, 2014 (continued)

<p align="center">Session 3: Semiconductor Technology - Part 2 1:30 pm - 5:00 pm</p>	3.1	1:30 pm - 2:00 pm	Ludger Kappius <i>Hella KGaA</i>	ZVEI Delta Qualification Matrix
	3.2	2:00 pm - 2:30 pm	Joop Verwijst <i>NXP Semiconductors</i>	Parameter Shift Analysis
	3.3	2:30 pm - 3:00 pm	Anil Gandhi <i>Qualicent Analytics</i>	Advanced Analytics for Automotive Zero Defect
	3.4	3:00 pm - 3:30 pm	Tim Haifley <i>Altera</i>	A Complete Lifetime Distribution
<p>3:30 pm - 4:00 pm BREAK: Coffee, drinks, snacks (provided)</p>				
<p align="center">Session 3: (Continued)</p>	3.5	4:00 pm - 4:30 pm	Weiyen Kuo <i>TSMC</i>	Cpk Challenges in Nanometer Semiconductor Technology
	3.6	4:30 pm - 5:00 pm	Megan Smitter <i>GE Aviation</i>	Collaborative Approach For Practical Modeling of Microcircuit Failures in High-Reliability Applications
	3.7	5:00 pm - 5:30 pm	Tim Haifley <i>Altera</i>	Combining Data From Similar Tests: A Bayesian Approach
<p>5:30 pm - 7:30 pm DINNER (on own)</p>				
<p>Workshop Session - W.5</p>		7:30 pm - 9:30 pm	<p>Q100 Document Review & Discussion <i>Moderator: AEC Q100 Technical Committee</i></p>	

Thursday, April 24, 2014

COFFEE (provided)	7:30 am - 8:00 am	Continental Breakfast provided	
Workshop Session - W.6	8:00 am - 9:00 am	Known Good Die / Multi-Chip Module <i>Moderator: Tom Lawler, Lattice Semiconductor</i>	
Workshop Session - W.7	9:00 am - 10:00 am	MEMS <i>Moderator: Earl Fischer, Autoliv</i>	
	10:00 am - 10:30 am	BREAK: Coffee, drinks, snacks (provided)	
Workshop Session - W.8	10:30 am - 11:00 am	Touch Systems <i>Moderator: Joe Lucia, John Deere Electronic Solutions</i>	
Workshop Session - W.9	11:00 am - 11:30 am	System-Level ESD <i>Moderator: TBD</i>	
Workshop Session - W.10	11:30 am - 12:00 pm	PC Board Qualification <i>Moderator: James McLeish, DfR Solutions</i>	
WRAP-UP	12:00 pm - 12:30 pm	AEC Technical Committee	Closing Statements & Workshop Adjourned